Non Volatile Memories

# Semiconductor Memory Classification

RWM		NVRWM	ROM
Random Access	Non-Random Access	EPROM E <sup>2</sup> PROM	Mask-Programmed Programmable (PROM)
SRAM DRAM	FIFO LIFO Shift Register CAM	FLASH	

#### SD, SSD e HDD





2.5" SATA 6GB/s / 3D V-NAND / 550 MB/s read, 520 MB/s write

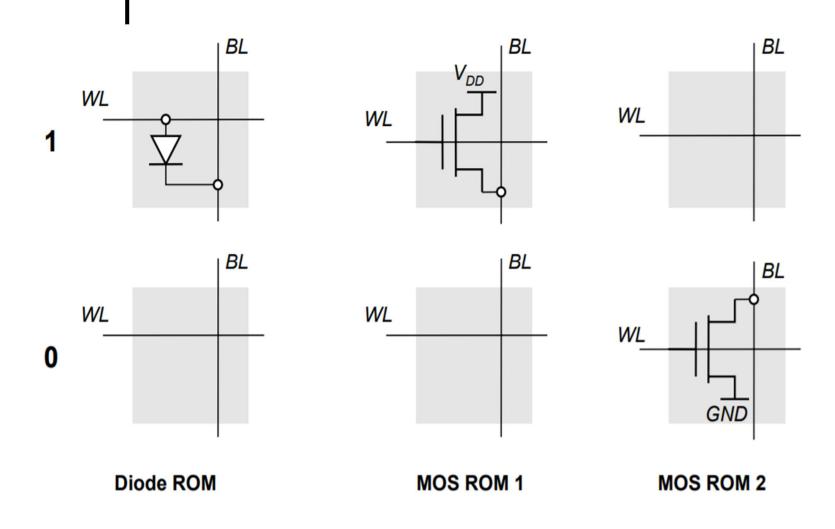


2.5" SATA vel max trasferimento 600MB/s, velocità continuativa 169 MB/s tempo medio di ricerca 12ms

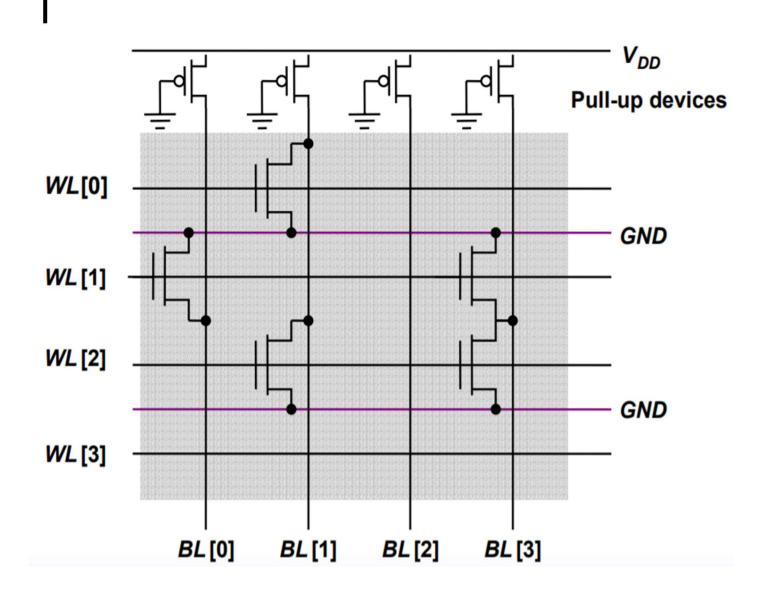
#### SD e SSD



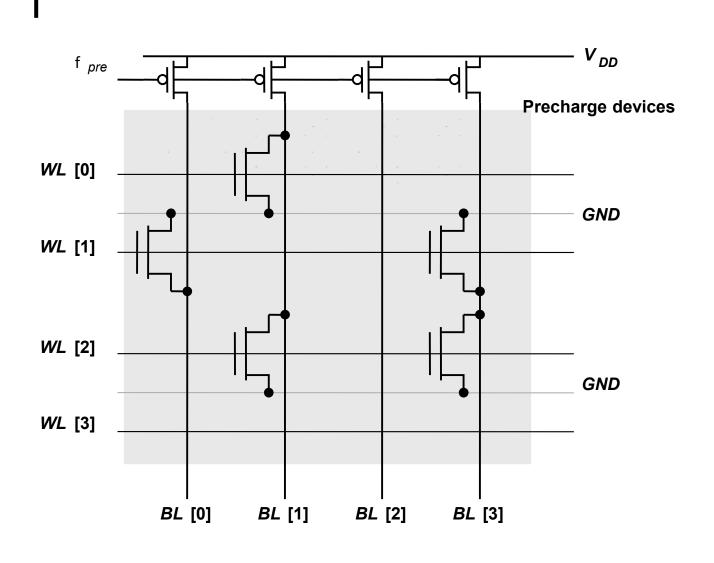
# • • Rom: Struttura



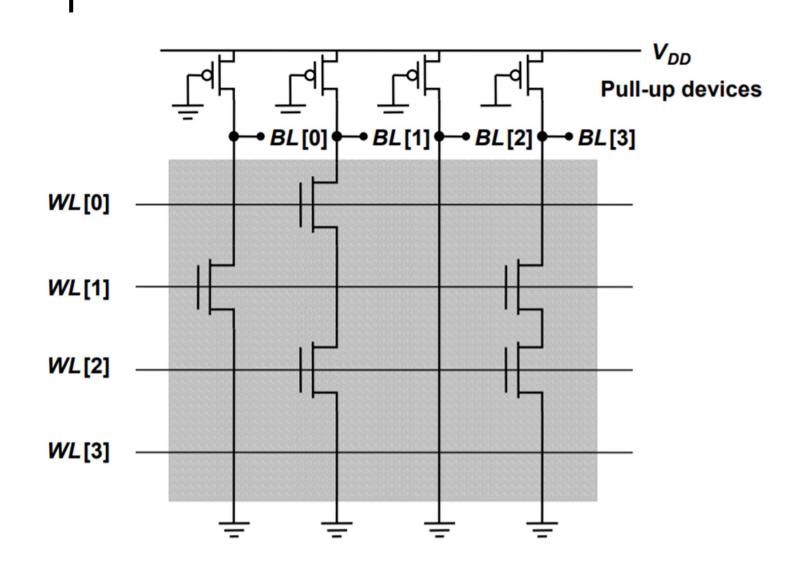
### MOS NOR ROM



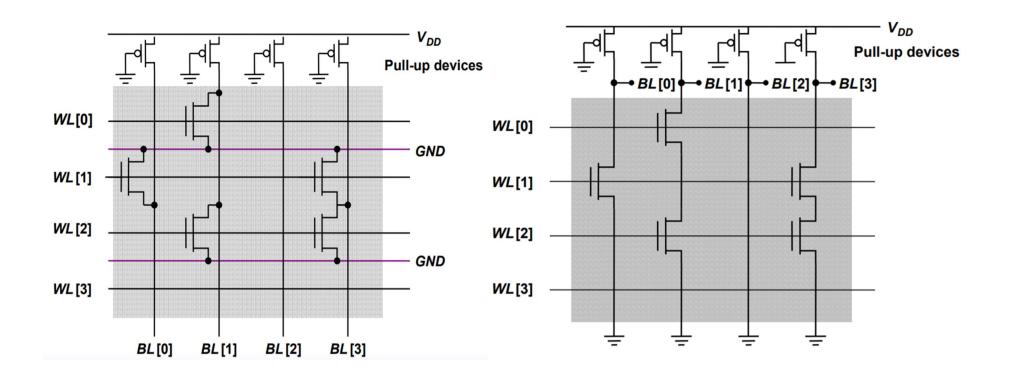
## Precharge NOR ROM



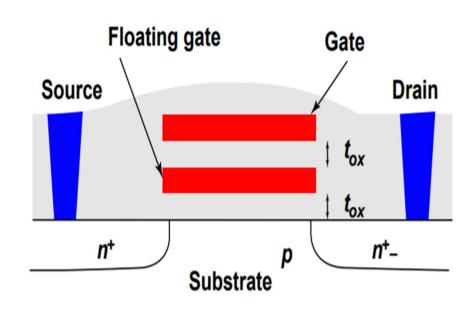
### MOS NAND ROM



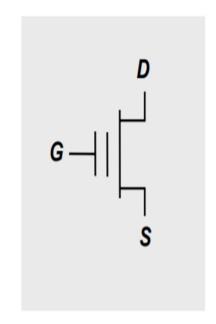
#### NAND vs NOR



# • • Floating Gate Transitor (Famos)

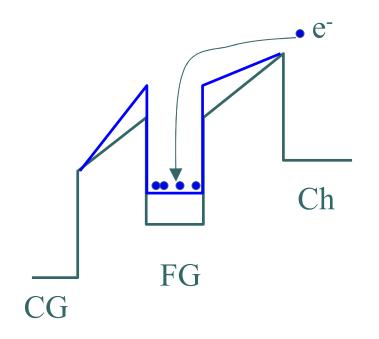


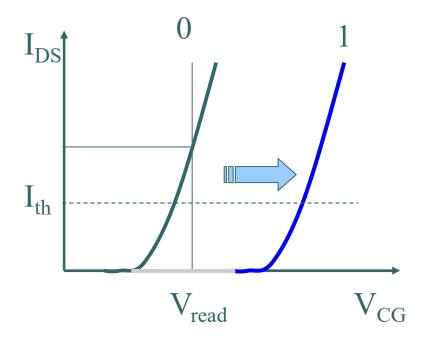


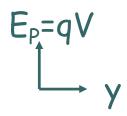


(b)Simbolo

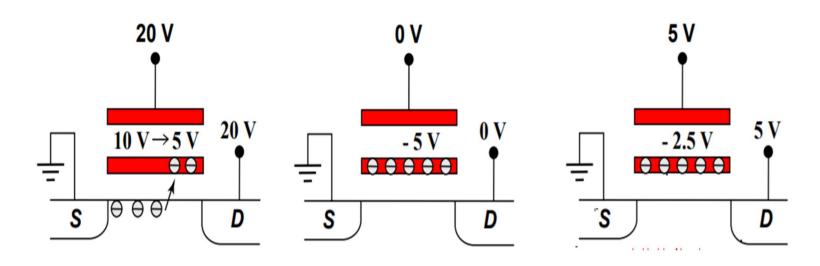
# MOS EPROM programming







# Programmazione Del Floating Gate Transitor

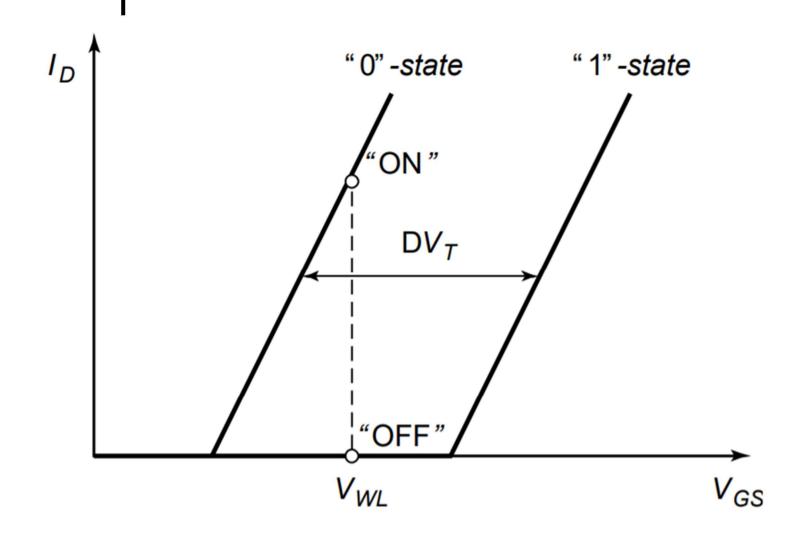


**Hot-carrier injection** 

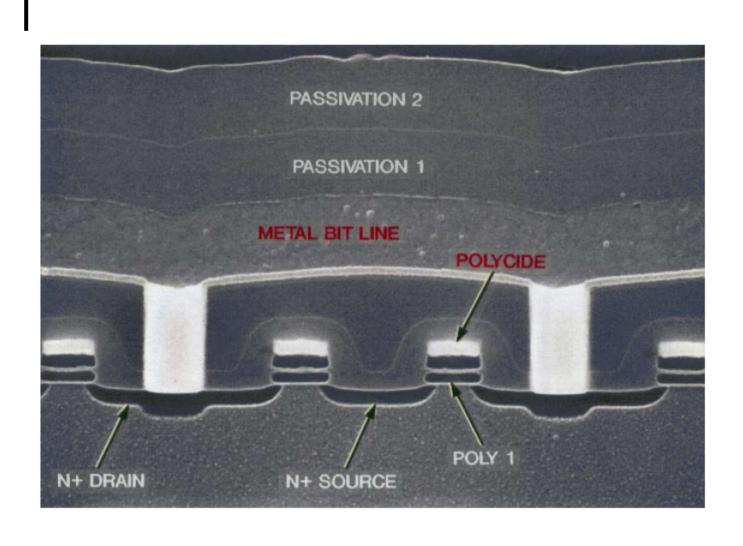
Removing programming voltage leaves charge trapped

Programming results in higher  $V_T$ .

Un Transitor a "Soglia-Programmabile"



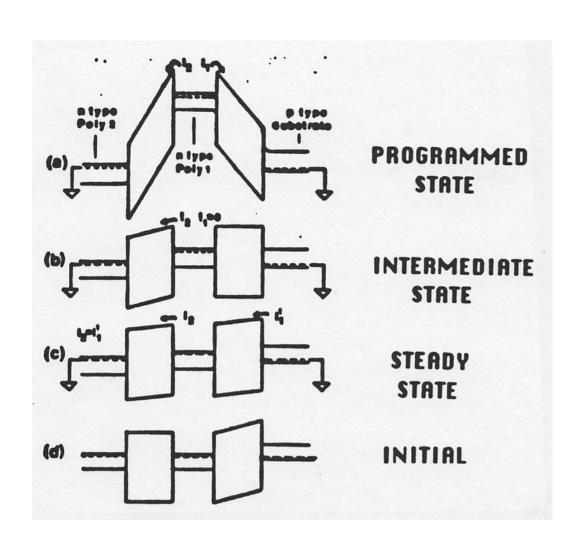
#### Cella EPPROM – SEM cross section



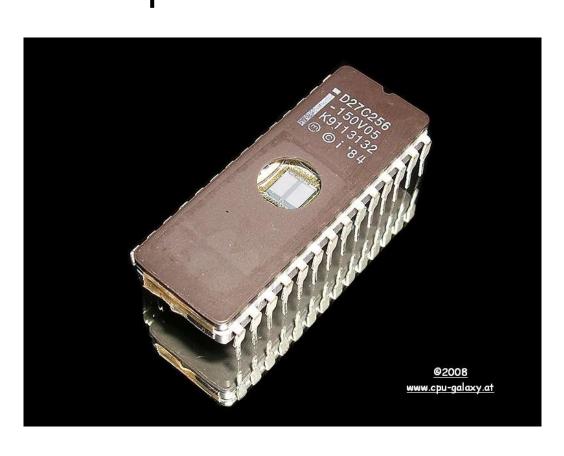
# Un Transitor a "Soglia-Programmabile"



# • • MOS EPROM erase by UV

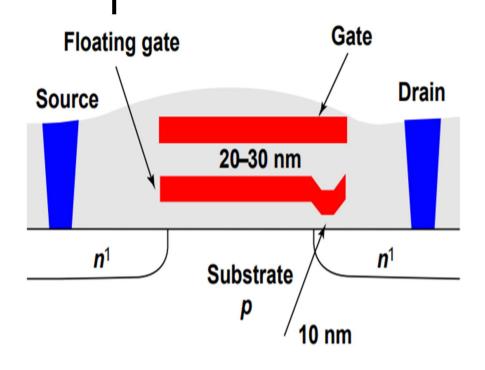


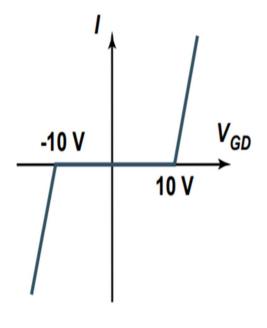
# MOS EPROM erase by UV





#### Transistore Flotox

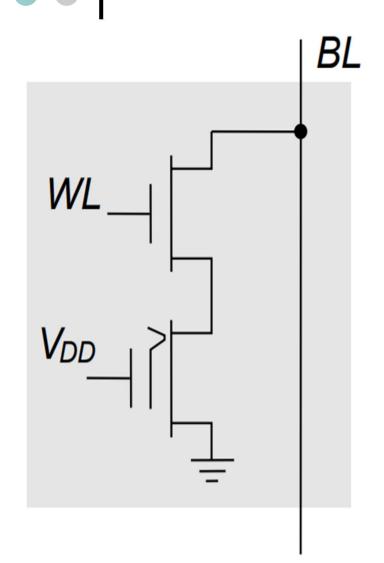




**FLOTOX** transistor

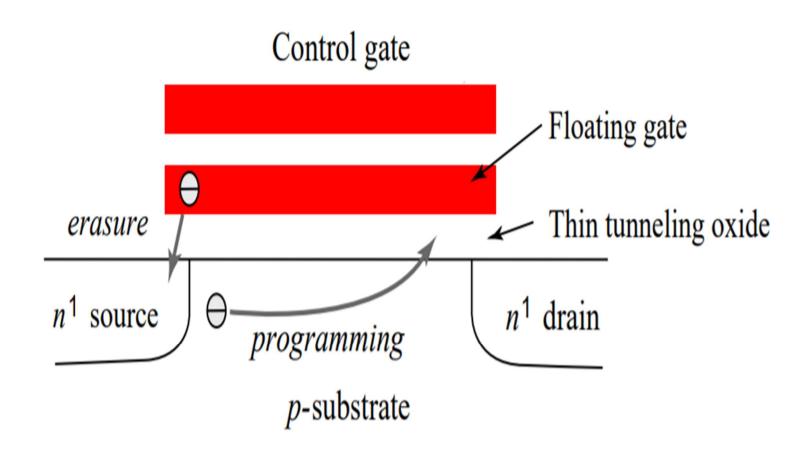
Fowler-Nordheim *I-V* characteristic

#### Cella EEPROM

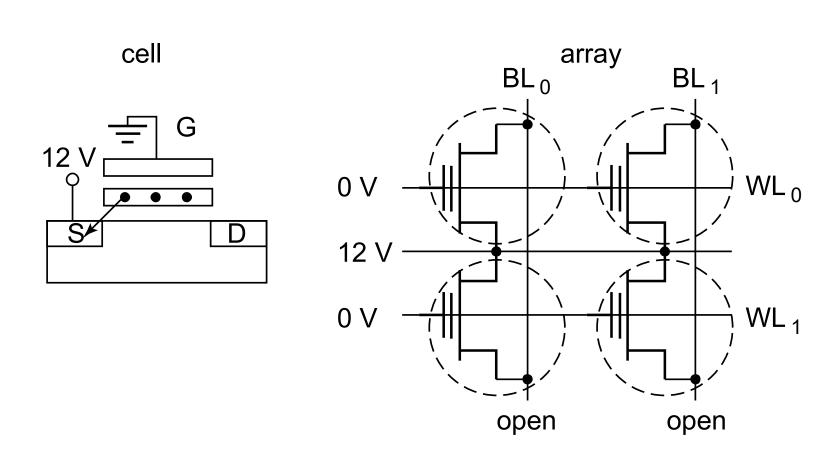


- Il controllo della soglia finale dopo la cancellazione è critico
- Il transistore non programmato potrebbe essere a soglia negativa.
- È necessario prevedere un transistore di selezione
- → cella a 2 transitor

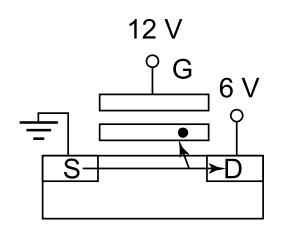
## Flash EEPROM

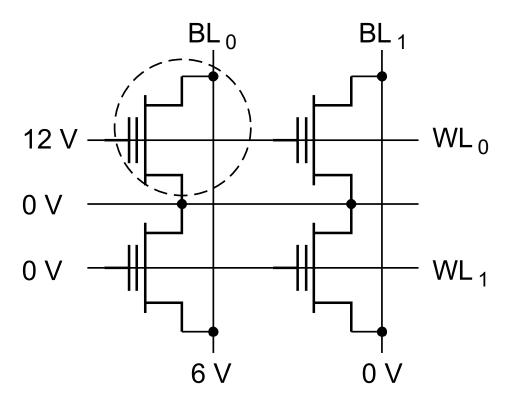


# NOR Flash Memory—Erase

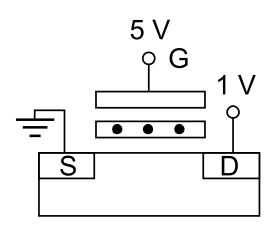


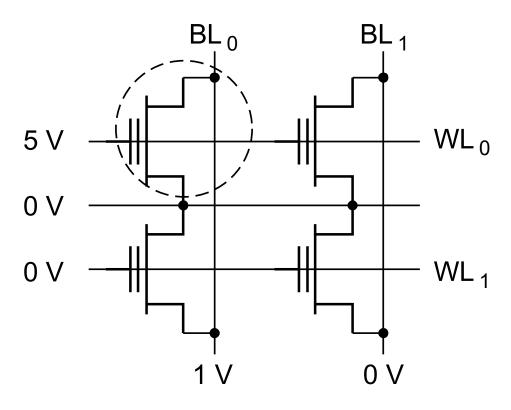
# NOR Flash Memory—Write



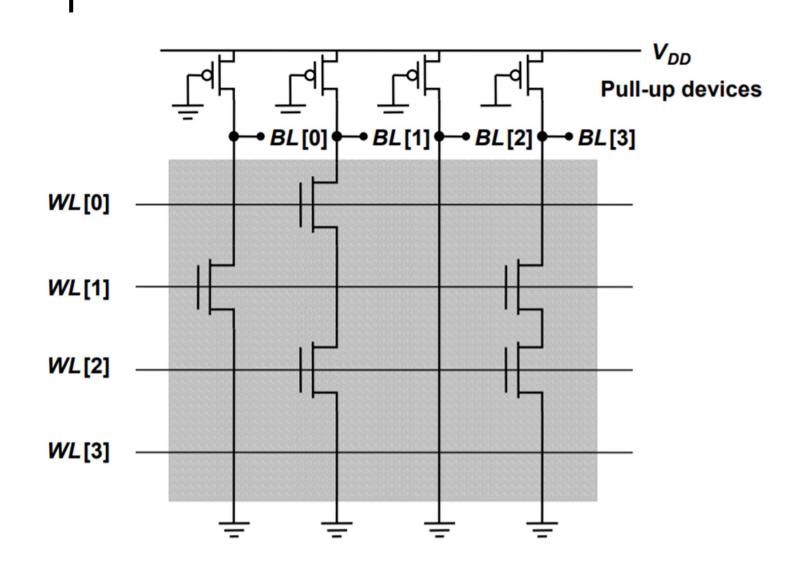


# NOR Flash Memory—Read

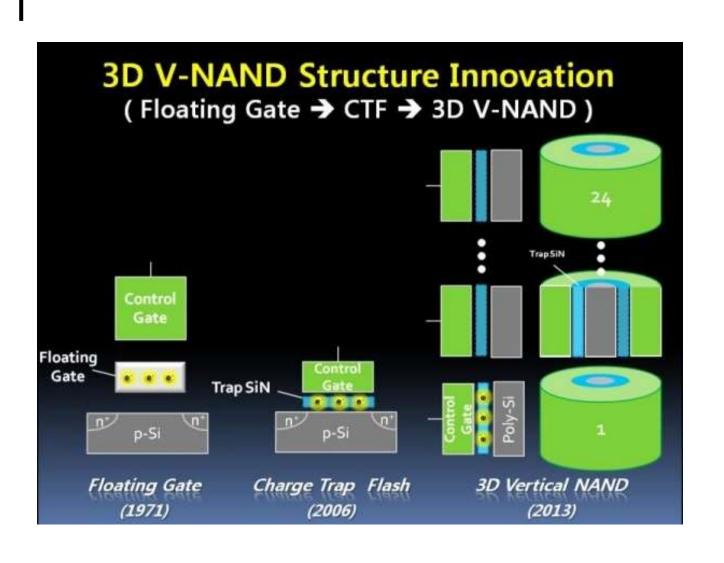




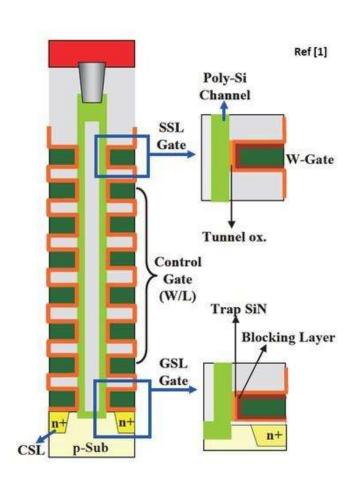
### MOS NAND ROM

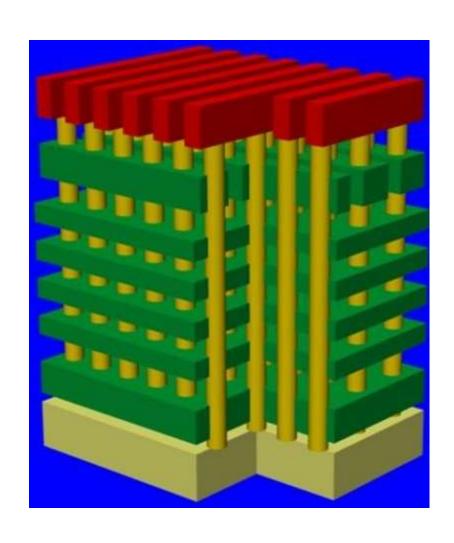


### Samsung 3D V-NAND



### Samsung 3D V-NAND





## Samsung 3D V-NAND

